

ATS2000 Technical Program Highlights

2 Tutorials

Tutorial 1: *High Performance & Delay Testing*, [Sudhakar M. Reddy](#), [U. of Iowa](#)

Tutorial 2: *SOC Testing & P1500 Standard*, [Yervant Zorian](#), [LogicVision Ltd.](#)

2 Keynote Speeches:

Keynote Speech 1: *Testing in the Fourth Dimension*,
[Vishwani D. Agrawal](#), [Lucent Technologies Ltd.](#)

Keynote Speech 2: *Challenges for the Academic Test Community*,
[Melvin A. Breuer](#), [U. of Southern California](#)

2 Industry Sessions

a. Computer-Aided Design Tools on Testing

[Wu-Tong Cheng](#), [Mentor Graphics Ltd.](#)

[Tom W. Williams](#), [Synopsys Ltd.](#)

[L.-T. Wang & Hsin-Po Wang](#), [SynTest Technologies Inc.](#)

[Yervant Zorian](#), [LogicVision Ltd.](#)

and more ...

b. Test Industry in Taiwan

Test service & ATE industry

1 Open Fringe Meeting on SOC Testing & P1500 Standard

Organizers: [Dr. Shianling Wu](#), [Lucent Technologies Ltd.](#) &
[Yervant Zorian](#), [LogicVision Ltd.](#)

2 Panel Discussions:

Panel 1: "Collaboration between Industry and Academia in Test Research."

Organizer: [Kwang-Ting \(Tim\) Cheng](#), [U. of California, Santa Barbara.](#)

Panel 2: "Mixed-Signal Testing."

Organizer: [Chin-Long Wey](#), [Michigan State U.](#)

19 Paper Sessions

Session A1: Analog & Mixed Signal Test I

Session A2: Memory Built-In Self-Test and Self-Diagnosis

Session B1: Analog & Mixed Signal Test II

Session B2: Fault Simulation & Timing Simulation

Session C1: Fault Analysis I

Session C2: Test Generation I

Session C3: Functional Testing

Session D1: Built-In Self-Test I

Session D2: Software Testing & Test Synthesis

Session D3: Embedded-Core Testing

Session E1: Memory Testing

Session E2: Test Generation II

Session E3: IDDQ Testing

Session F1: Built-In Self-Test II

Session F2: Testability Analysis and Design for Testability

Session F3: Fault Tolerance

Session G1: Fault Analysis II

Session G2: Low-Power Testing

Session G3: Self-Checking Circuits